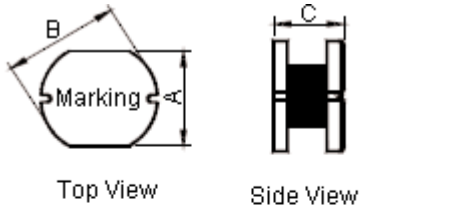
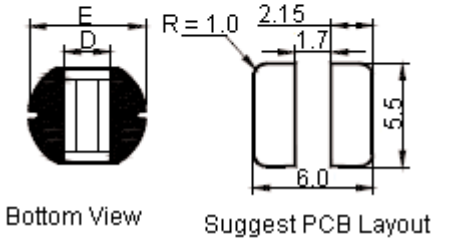
	PART NO.	REVISIONS								
		ECN #	REV	DESCRIPTION	DRAWN	DATE	CHECKD	DATE	APPRVD	DATE
multicomp	MCSD75-330KU	-	A	RELEASED	Arun	10/2/11	Jagan	10/2/11	Farnell	24/2/11

Configurations and Dimensions



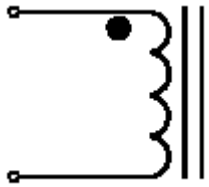


Dimensions : Millimetres

A	7 ±0.3 mm	-
B	7.8 ±0.3 mm	-
C	5 ±0.5 mm	-
D	3 mm	(Reference)
E	8 ±0.5 mm	-

Marking : 330

Schematic Diagram



RoHS Compliant

Note:

(1) Wire Ø0.35mm x 1P 2UEWF 155°C
(2) 30.5TS (Reference)

Test Data for Mechanical

Test Item	A mm	B mm	C mm	D mm	E mm
Specification	**7 ±0.3**	**7.8 ±0.3**	**5 ±0.5**	**3 (Reference)**	**8 ±0.5**
1	7.05	7.82	4.99	2.26	7.79
2	7.06		5.05	2.25	7.75
3	7.08	7.84	5.06	2.28	7.81
4	7.04	7.81	5.01	2.23	7.79
5	7.09	7.85	5.07	2.27	
Average	**7.06**	**7.83**	**5.04**	**2.26**	**7.79**

Electrical Characteristics (at 25°C)

Test Condition		
100KHz 0.25V	L	33µH ±10%
at 25°C	DCR	130mΩ (Maximum)
100KHz 0.25V I_{rms} = 1.20A	ΔT	Temperature Rise 40°C (Maximum)

Operating temperature : -55°C to +130°C

TOLERANCES:

UNLESS OTHERWISE SPECIFIED, DIMENSIONS ARE FOR REFERENCE PURPOSES ONLY.

DRAWN BY:	DATE:
Arun	10/02/11
CHECKED BY:	DATE:
Jagan	10/02/11
APPROVED BY:	DATE:
Farnell	24/02/11

DRAWING TITLE: Inductor

SIZE	DWG NO.	ELECTRONIC FILE	REV
A	M10003025	SD75-330KU	A

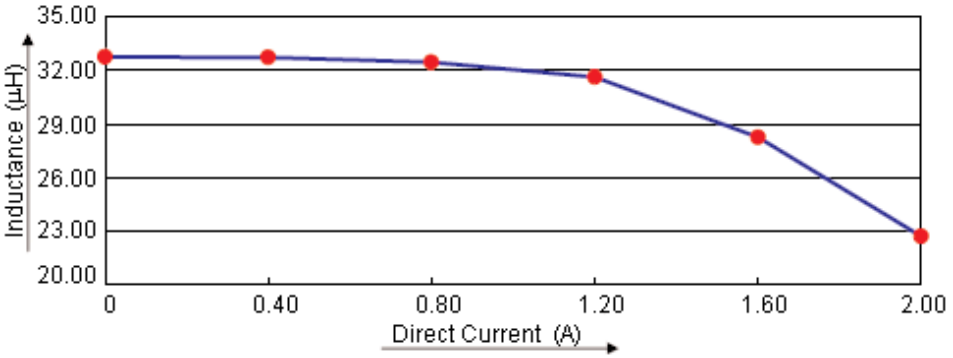
SCALE: NTS | U.O.M.: mm | SHEET: 1 OF 3

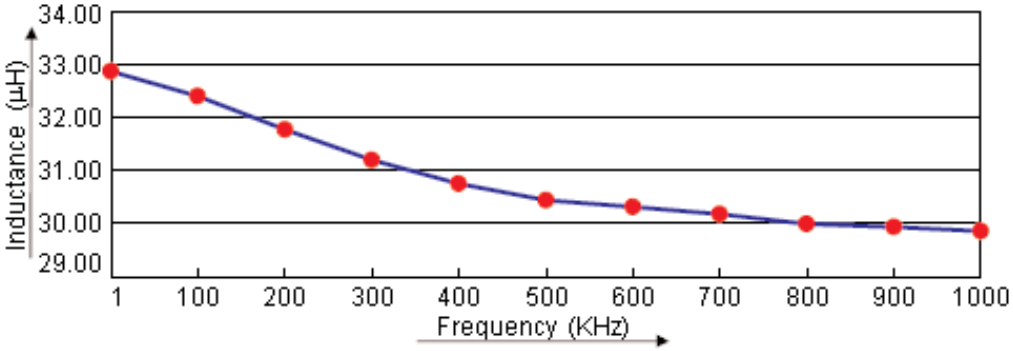
multicomp	PART NO. MCSD75-330KU	REVISIONS									
		ECN #	REV	DESCRIPTION	DRAWN	DATE	CHECKD	DATE	APPRVD	DATE
		-	A	RELEASED	Arun	10/2/11	Jagan	10/2/11	Farnell	24/2/11

Test Data for Electrical

Test Item	L µH	DCR mΩ	ΔT
Condition	**100KHz 0.25V**	**at 25°C**	**100KHz 0.25V I_{rms} = 1.20A**
Specification	**33 ±10%**	**130 (Maximum)**	**Temperature Rise 40°C (Maximum)**
1	32.13	89.5	OK
2	31.93	88.6	OK
3	31.95	91.8	OK
4	31.82	87.2	OK
5	31.78	87	OK
Average	**31.92**	**88.82**	**OK**

Electric Characteristics





TOLERANCES:

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Arun	10/02/11
CHECKED BY:	DATE:
Jagan	10/02/11
APPROVED BY:	DATE:
Farnell	24/02/11

DRAWING TITLE: Inductor

SIZE	DWG NO.	ELECTRONIC FILE	REV
A	M10003025	SD75-330KU	A

SCALE: NTS | U.O.M.: mm | SHEET: 2 OF 3

PART NO.	REVISIONS								
MCSD75-330KU	ECN #	REV	DESCRIPTION	DRAWN	DATE	CHECKD	DATE	APPRVD	DATE
	-	A	RELEASED	Arun	10/2/11	Jagan	10/2/11	Farnell	24/2/11

Reliability Test

Test Item	Specifications	Test Method and Remarks
Operating temperature range	-55°C to +130°C	Including temperature rise due to self-generated heat.
Storage condition	Ambient temperature : 0°C to 40°C Humidity : Below 70%RH	To maintain the solderability of terminal electrodes, care must be taken to control temperature and humidity in the storage area.
Moisture sensitivity	Appearance : No abnormality No damage DCR change : Within ±20% Inductance change : Within ±20%	According to J-STD-020B level 3 Test condition : 60°C 60% RH Test duration : 40 hours Recovery : 1 to 2 hours of recovery under the standard condition after the removal from the test chamber.
Solderability	All termination shall exhibit a continuous solder coating free from defects for a minimum of 90% of the surface area of any individual lead.	According to J-STD-002B Steam aging category : 97°C 98% RH Steam aging duration : 8 hours Solder : Lead-free solder Solder temperature : 260 ±5°C Dip time : 5 +0/-0.5 seconds.

Material List

No.	Item	Material Description
1	Core	R5A CDR7.8 x 5 (ST) B2.9 F2.5
2	Wire	Ø0.35mm x 1P 2UEWF 155°C
3	Solder (Lead Free)	Sn99.3% / Cu0.7%

Part Number Table

Description	Part Number
Inductor, 33µH, 10%, SMD	MCSD75-330KU

http://www.farnell.com

http://www.newark.com

http://www.cpc.co.uk

TOLERANCES:

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DRAWN BY:	DATE:
Arun	10/02/11
CHECKED BY:	DATE:
Jagan	10/02/11
APPROVED BY:	DATE:
Farnell	24/02/11

DRAWING TITLE: Inductor

SIZE	DWG NO.	ELECTRONIC FILE	REV
A	M10003025	SD75-330KU	A

SCALE: NTS | U.O.M.: mm | SHEET: 3 OF 3